

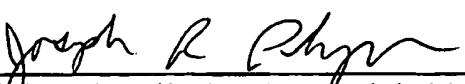
Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 5244-0107-2	SERIAL NO. 09/504,965
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Xiaoan HOU, et al.	
				FILING DATE February 16, 2000	GROUP 2622
FOREIGN PATENT DOCUMENTS					
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO
JP	AA	0 241 273	10/14/87	EUROPE	XX
JP	AB	0 354 703	02/14/90	EUROPE	XX
JP	AC	59-064956	04/13/84	JAPAN W/ENGLISH ABSTRACT	XX
JP	AD	DE 350 7479	09/04/86	GERMAN W/ENGLISH ABSTRACT	XX
JP	AE	0 159 158	10/23/85	EUROPE	XX
JP	AF	60-167568	08/30/85	JAPAN W/ENGLISH ABSTRACT	XX
JP	AG	60-173968	09/07/85	JAPAN W/ENGLISH ABSTRACT	XX
JP	AH	60-182851	09/18/85	JAPAN W/ENGLISH ABSTRACT	XX
JP	AI	60-218961	11/01/85	JAPAN W/ENGLISH ABSTRACT	XX
JP	AJ	60-194472	10/02/85	JAPAN W/ENGLISH ABSTRACT	XX
JP	AK	62-162551	07/18/87	JAPAN W/ENGLISH ABSTRACT	XX
JP	AL	58-138162	08/16/83	JAPAN W/ENGLISH ABSTRACT	XX
JP	AM	59-099846	06/08/84	ENGLISH ABSTRACT JPX	XX
JP	AN	58-138148	08/16/83	JAPAN W/ENGLISH ABSTRACT	XX
JP	AO	58-165452	09/30/83	JAPAN W/ENGLISH ABSTRACT	XX
JP	AP	57-119541	07/26/82	ENGLISH ABSTRACT JPX	XX
JP	AQ	57-192167	11/26/82	JAPAN W/ENGLISH ABSTRACT	XX
JP	AR	57-119537	07/26/82	ENGLISH ABSTRACT JPX	XX
JP	AS	64-086180	03/30/89	JAPAN W/ENGLISH ABSTRACT	XX
JP	AT	1-138524	05/31/89	JAPAN W/ENGLISH ABSTRACT	XX
JP	AU	2-060763	03/01/90	JAPAN W/ENGLISH ABSTRACT	XX
JP	AV	59-221165	12/12/84	JAPAN W/ENGLISH ABSTRACT	XX
JP	AW	59-117372	07/06/84	JAPAN W/ENGLISH ABSTRACT	XX
JP	AX	59-117845	07/07/84	JAPAN W/ENGLISH ABSTRACT	XX
JP	AY	63-269664	11/07/88	JAPAN W/ENGLISH ABSTRACT	XX
JP	AZ	63-269665	11/07/88	JAPAN W/ENGLISH ABSTRACT	XX
JP	AAA	64-024561	01/26/89	JAPAN W/ENGLISH ABSTRACT	XX
JP	AAB	64-050671	02/27/89	JAPAN W/ENGLISH ABSTRACT	XX
JP	AAC	63-269663	11/07/88	JAPAN W/ENGLISH ABSTRACT	XX
JP	AAD	62-132464	06/15/87	JAPAN W/ENGLISH ABSTRACT	XX
JP	AAE	58-175342	10/14/83	JAPAN W/ENGLISH ABSTRACT	XX
JP	AAF	63-023469	01/30/88	ENGLISH ABSTRACT W/DRAWING JPX	XX
JP	AAG	64-012657	01/17/89	JAPAN W/ENGLISH ABSTRACT	XX
JP	AAH	1-181373	07/19/89	JAPAN W/ENGLISH ABSTRACT	XX

Examiner *Joseph R. Phys*

Date Considered *4/22/05*

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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		FILING DATE February 16, 2000		GROUP 2622	
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		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO
JP	AA	63-178666	07/22/88	JAPAN W/ENGLISH ABSTRACT	XX
JP	AB	60-048661	03/16/85	JAPAN W/ENGLISH ABSTRACT	XX
JP	AC	59-064956	04/13/84	JAPAN W/ENGLISH ABSTRACT	XX
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JP	AE	60-048662	03/16/85	JAPAN W/ENGLISH ABSTRACT	XX
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JP	AG	64-012657	01/17/89	JAPAN W/ENGLISH ABSTRACT	XX
JP	AH	63-242060	10/07/88	JAPAN W/ENGLISH ABSTRACT	XX
JP	AI	2-172348	07/03/90	JAPAN W/ENGLISH ABSTRACT	XX
JP	AJ	62-049772	03/04/87	ENGLISH ABSTRACT W/DRAWING	JPX XX
JP	AK	64-082010	03/28/89	JAPAN W/ENGLISH ABSTRACT	XX
JP	AL	64-059210	03/06/89	JAPAN W/ENGLISH ABSTRACT	XX
JP	AM	63-299573	12/07/88	JAPAN W/ENGLISH ABSTRACT	XX
JP	AN	63-136875	06/09/88	JAPAN W/ENGLISH ABSTRACT	XX
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Examiner	<i>Joseph R. Ryan</i>			Date Considered	4/22/05
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